

<b>STN</b>	<b>Polovodičové súčiastky</b> <b>Mechanické a klimatické skúšobné metódy</b> <b>Časť 12: Vibrácie, premenlivá frekvencia</b>	<b>STN</b> <b>EN IEC 60749-12</b>  35 8799
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Semiconductor devices - Mechanical and climatic test methods - Part 12: Vibration, variable frequency

Táto norma obsahuje anglickú verziu európskej normy.  
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 01/19

Obsahuje: EN IEC 60749-12:2018, IEC 60749-12:2017

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**EN IEC 60749-12**

NORME EUROPÉENNE

EUROPÄISCHE NORM

March 2018

ICS 31.080.01

Supersedes EN 60749-12:2002

English Version

**Semiconductor devices - Mechanical and climatic test methods -  
Part 12: Vibration, variable frequency  
(IEC 60749-12:2017)**

Dispositifs à semiconducteurs - Méthodes d'essais  
mécaniques et climatiques - Partie 12: Vibrations,  
fréquences variables  
(IEC 60749-12:2017)

Halbleiterbauelemente - Mechanische und klimatische  
Prüfverfahren - Teil 12: Schwingen, variable Frequenz  
(IEC 60749-12:2017)

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels**

**EN IEC 60749-12:2018 (E)****European foreword**

The text of document 47/2386/CDV, future edition 2 of IEC 60749-12, prepared by IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 60749-12:2018.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2018-10-17
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IEC 60068-2-6      NOTE      Harmonized as EN 60068-2-6.



IEC 60749-12

Edition 2.0 2017-12

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE

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**Semiconductor devices – Mechanical and climatic test methods –  
Part 12: Vibration, variable frequency**

**Dispositifs à semiconducteurs – Méthodes d’essais mécaniques et climatiques –  
Partie 12: Vibrations, fréquences variables**



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IEC Central Office  
3, rue de Varembe  
CH-1211 Geneva 20  
Switzerland

Tel.: +41 22 919 02 11  
Fax: +41 22 919 03 00  
[info@iec.ch](mailto:info@iec.ch)  
[www.iec.ch](http://www.iec.ch)

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# NORME INTERNATIONALE

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**Semiconductor devices – Mechanical and climatic test methods –  
Part 12: Vibration, variable frequency**

**Dispositifs à semiconducteurs – Méthodes d’essais mécaniques et climatiques –  
Partie 12: Vibrations, fréquences variables**

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**SEMICONDUCTOR DEVICES – MECHANICAL  
AND CLIMATIC TEST METHODS –**
**Part 12: Vibration, variable frequency****FOREWORD**

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International Standard IEC 60749-12 has been prepared by IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 2002. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) alignment with MIL-STD-883J Method 2007, Vibration, variable frequency.

The text of this International Standard is based on the following documents:

CDV	Report on voting
47/2386/CDV	47/2434/RVC



Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 60749 series, published under the general title *Semiconductor devices – Mechanical and climatic test methods*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

## **SEMICONDUCTOR DEVICES – MECHANICAL AND CLIMATIC TEST METHODS –**

### **Part 12: Vibration, variable frequency**

#### **1 Scope**

This part of IEC 60749 describes a test to determine the effect of variable frequency vibration, within the specified frequency range, on internal structural elements. This is a destructive test. It is normally applicable to cavity-type packages.

NOTE This test method describes a swept sine test. A random vibration test is described in JEDEC document JESD 22-B103.

#### **2 Normative references**

There are no normative references in this document.

**koniec náhľadu – text ďalej pokračuje v platenej verzii STN**